Se	earc	n	NO	es	
		Ш			
		Ш			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/559,966	IMADA ET AL.
Examiner	Art Unit
Binh X. Tran	1792

SEARCHED				
Class	Subclass	Date	Examiner	
216	11	12/21/2007	ВТ	
216	40	12/21/2007	ВТ	
216	44	12/21/2007	ВТ	
216	53	12/21/2007	ВТ	
216	83	12/21/2007	вт	
,				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
Search inventors' name and keywords using databases in EAST	12/21/2007	ВТ
		·
<del> </del>		